Editorial

THIS ISSUE on the applications of National Instruments LabVIEW software in engineering education is a milestone in the history of the journal. For the first time we are devoting a whole issue to work with a software that has found applications in many areas of engineering education. So, although we show applications with a specific software package, its usefulness is interdisciplinary, and yet it is not a general purpose software for office use such as spreadsheet packages.

In cooperating with National Instruments—the developers and vendors of the software—the issue has a CD-ROM attached which contains in addition to the papers and the Virtual Instruments, an evaluation version of LabVIEW. It is clear from the sources of the paper contributions that LabVIEW is used in engineering education all over the world. In the current issue we have contributions from Singapore, Switzerland, Australia and the USA. The publication of the issue has also entailed a new dimension in logistics for its production. All papers submitted in electronic form were copyedited, typeset and transmitted electronically to the authors for correction. Upon return of the corrected papers, they were transmitted in bulk to our guest editor, Nesimi Ertugrul at the University of Adelaide. Nesimi produced the master CD. This was then sent to Ravi Marawar of National Instruments in the USA for final duplication and production. The completed set of CD's was then sent to Oxford for inclusion with the printed issue. A truly global venture.

The invited guest editors Nesimi Ertugrul in Adelaide and Jim Henry at the University of Tennessee provided invaluable guidance with their expertise in putting the issue together. Ravi Marawar of National Instruments was continuously briefed and consulted during the progression of the editorial process. With their help we are planning to continue dialog on the applications of LabVIEW in engineering education on an interactive forum on the journal website. I wish to express my deep gratitude to Nesimi and all the others involved in producing this special issue, for their excellent work and devotion all along the way to publication.

Michael Wald